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# 2012 IEEE International Instrumentation and Measurement Technology Conference

"Smart Measurements for a Sustainable Environment"



Congress Graz Graz, Austria May 13–16, 2012





# **Call for Papers**

## Extended Abstract Deadline November 30<sup>th</sup>

The conference focuses on research, development and applications in the field of instrumentation and measurement science and technology. The conference also includes **Industrial Tracks** reflecting current opportunities for the mutually beneficial fusion of basic research and industrial applications. These tracks are highlighted by **Keynote Presentations** and are thematically coupled with **Tutorials** on May 13<sup>th</sup>.

A **Student Paper Contest** will be held for both graduate and undergraduate student papers, with cash awards for the best papers and travel subsidies depending on the student's location.

BEST PAPER INDUSTRIAL TRACK AWARD

Authors no more than 35 years old will be eligible for a **special Best Paper competition** to be held in each of the **three Industrial Track topics**.

Conference topics include, but are not necessarily limited to:



#### **FUNDAMENTALS**

Advanced metrology Education and e-learning Measurement uncertainty Modeling of signals and systems Quantities, units & standards

Chemical & biological sensors

## **SENSORS AND TRANSDUCERS**

Electrical & power measurements
Energy harvesting
Optical sensing
Sensor array processing
Smart sensors
Wireless sensors & sensor networks

# MEASUREMENTS OF PHYSICAL QUANTITIES

Dielectric & magnetic measurements
Mass & density measurements
Mechanical measurements
Moisture & humidity measurements
Properties of liquids
Temperature measurements

#### **MEASUREMENT SYSTEMS**

A/D & D/A converters
Automated tests & diagnostics
Calibration & self-calibration
Condition & state monitoring
Distributed measurement systems
Instrumentation for harsh environments
Instrumentation for mobile use
Systems engineering
Virtual measurement systems

#### **MEASUREMENT APPLICATIONS**

Applied spectroscopy
Automotive & transportation
Avionics & aerospace
Biomedical monitoring
Electric drive train instrumentation
Environmental monitoring
Radiation instrumentation & sensing
Remote sensing
RF, microwave & capacitive sensing
Robotics and HMI
Security & biometrics
Ships & marine technology
Telecommunications

#### SIGNAL AND IMAGE PROCESSING

Cognitive informatics
Data pre- & post-processing
Image processing & pattern recognition
Inverse problems
Measurement data management
Sensor fusion
Signal detection & classification
Signal reconstruction

## **INDUSTRIAL APPLICATIONS**

Chemical and biological measurements
Combustion process sensing & instrumentation
Energy efficiency & renewables
Fault tolerant sensor systems
Industrial process tomography
Material analysis
Multiphase flow measurement
Oil field sensing & drilling instrumentation
Plant optimization
Power-train testing
Process instrumentation
Quality assurance & authentication
Sustainable propulsion technologies

Prospective authors are invited to submit extended abstracts (3-4 pages) via the I<sup>2</sup>MTC conference website (<a href="http://imtc.ieee-ims.org/">http://imtc.ieee-ims.org/</a>). The abstract should report on original research results of theoretical or applied nature and should explain the significance of the contribution to the corresponding research field. The manuscripts must be prepared according to the abstract preparation guidelines provided on the I<sup>2</sup>MTC website.

The extended abstracts will be reviewed by the Technical Program Committee. All papers presented at the conference will be published in the **Conference Proceedings** and via **IEEE Xplore**. Important deadlines are:

- November 30, 2011
- January 15, 2012
- March 11, 2012
- Deadline for submission of extended abstracts
- Notification of authors of paper acceptance/rejection
  - Deadline for submission of camera-ready papers













